

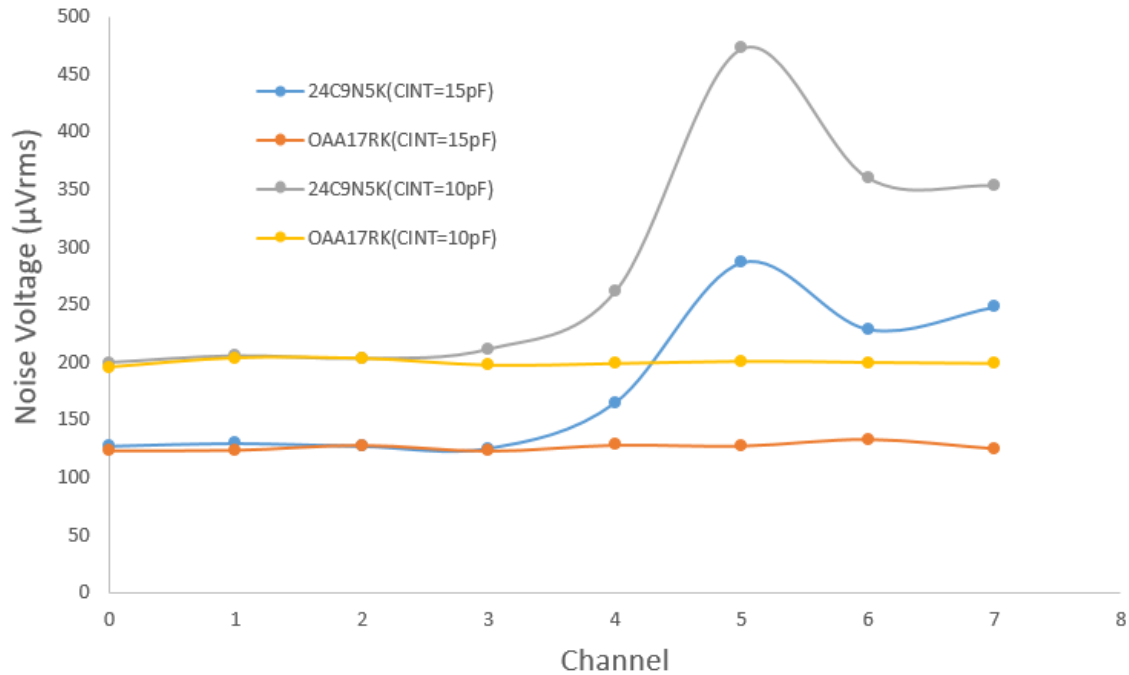
Sample and test 8 pieces of IVC102 from 24C9N5K, and compare with 8 pieces of IVC102 from qualified batch OAA17RK under the same circuit; 24C9N5K-IVC102 # 0~7 and OAA17RK-IVC102 # 0~7 are respectively in the same position on the same circuit board, and they are tested through chip replacement.

$C_{IN} = 300\text{pF}$

$T_{INT} = 200\text{us}$

The noise results of 2048 tests are shown in the figure below:

Noise VS Channel



The chip 24C9N5K-IVC102 # 4 24C9N5K-IVC102 # 5 24C9N5K-IVC102 # 6 24C9N5KIVC102 # 7 noise index is unqualified

Data is converted from AD acquisition, AD noise parameter: 1.8 ppm of FSR, rms

